

Precision Tiltmeter for the EDM Experiment

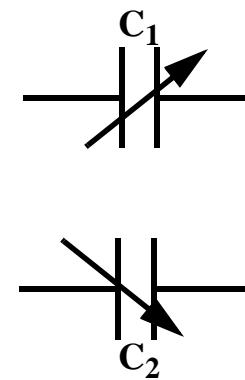
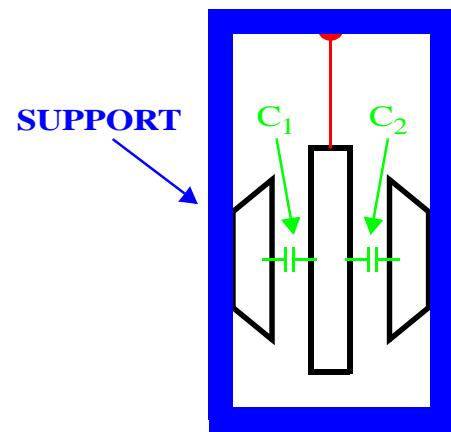
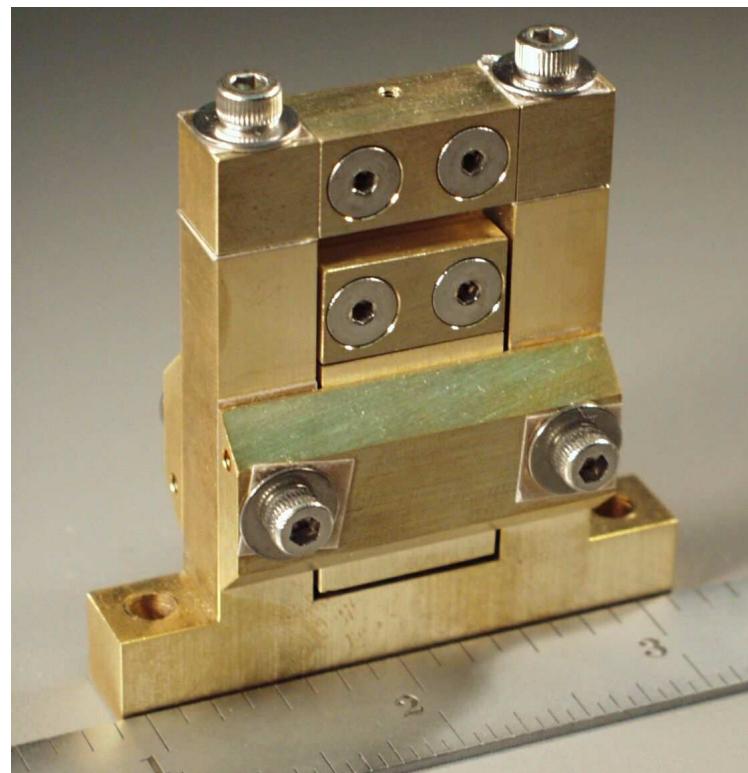
Sergio Rescia

- **Tiltmeter Principle**
- **Revised Specifications**
- **Tiltmeter Characterization:short term (~100 s) stability**

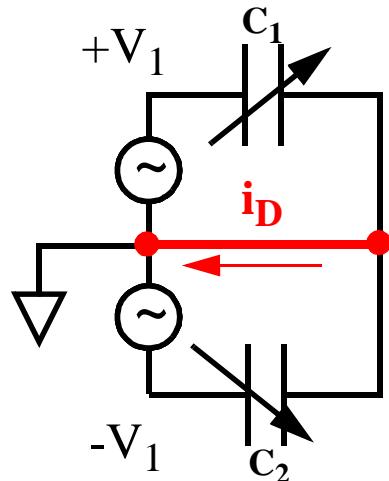
Acknowledgment:

The EDM Collaboration, especially G. Bennet, R. Burns, W. Morse, Y. Semertzidis, L. Snydstrup

Tiltmeter



Readout: AC Bridge

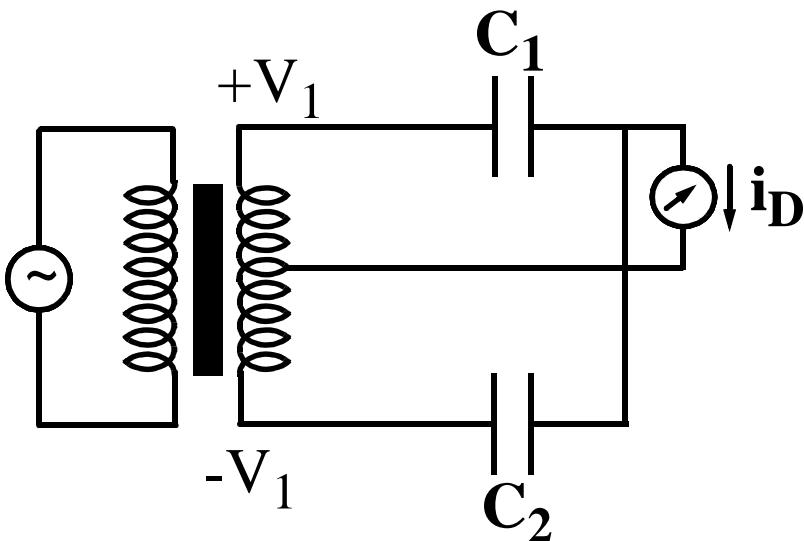


$$C_1 - C_2 = \varepsilon A / (\delta x - x_0) - \varepsilon A / (\delta x + x_0) = 2 C_0 \delta x / x_0$$

$A = 400 \text{ mm}^2$ $x_0 = 75 \mu\text{m}$ $C_0 = C_1 = C_2 = 50 \text{ pF}$

$l = 30 \text{ mm}$ $\delta\theta = 1 \text{ nrad}$ $\delta x = \delta\theta l = 30 \cdot 10^{-12} \text{ m}$

$\delta C = 40 \text{ aF}$ for $\delta\theta = 1 \text{ nrad}$



$$i_D = V_1 \omega (C_1 - C_2)$$

for $V_1 = 1 \text{ V}$, $f = 16 \text{ kHz}$

$$i_D = 4 \text{ pA}$$

Revised specifications

Is it possible to have 1 prad (10^{-12} radians) sensitivity?

Given a transducer gain of 40 aF per nrad, this requires having a noise in capacitance of less than ~ few zF
(zeptofarad = 1×10^{-21} F)

ELECTRICAL NOISE

$$\overline{C_n^2} = \frac{1}{V_1^2} \left(\overline{e_n^2} C_T^2 + \frac{\overline{i_n^2}}{\omega_0^2} \right) BW$$

$C_T = 1 \text{ nF}$	}	$C_n = 3 \times 10^{-21} \text{ F} = 3 \text{ zF}$
$e_n = 1 \text{ nV/Hz}^{1/2}$		
$V_1 = 3 \text{ V}$		
$BW = 10^{-4} \text{ Hz}$		
$(TC = 2500 \text{ s})$		

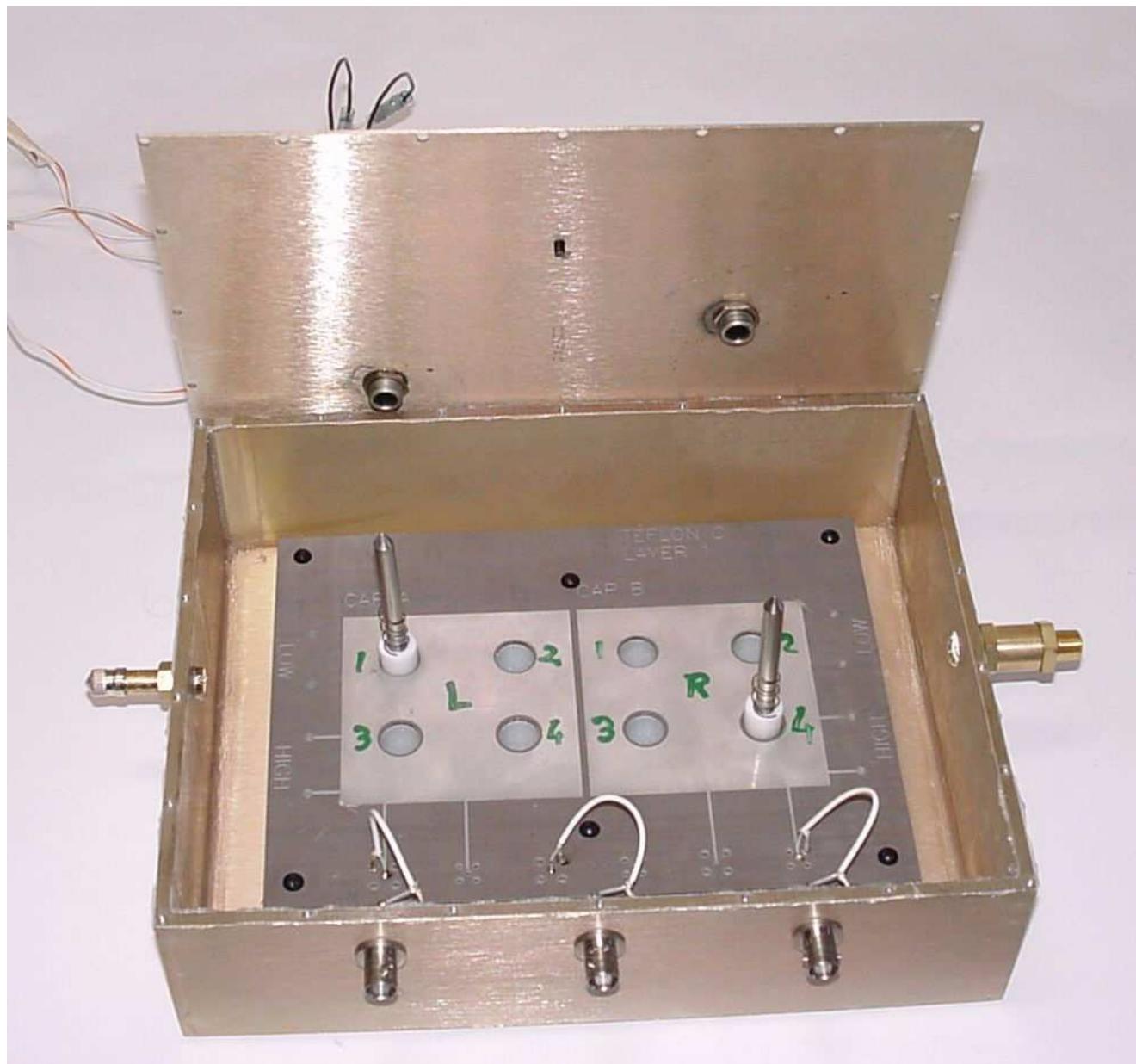
Best noise results by Jones: ~ 40 zF for BW = 1 Hz by extreme methods ($V_{exit.} = 100\text{V}$, $Q = 100$ resonant circuit)
Best published results: 1 zF for small capacitance

In practice: limited by vibrational noise, not electrical noise

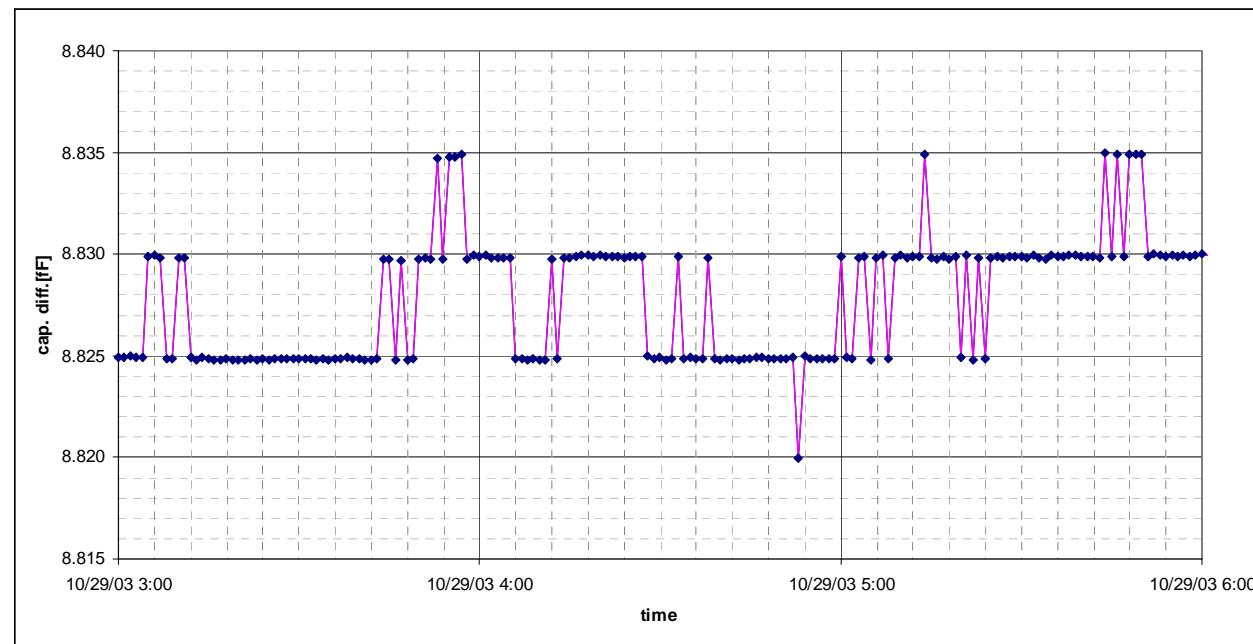
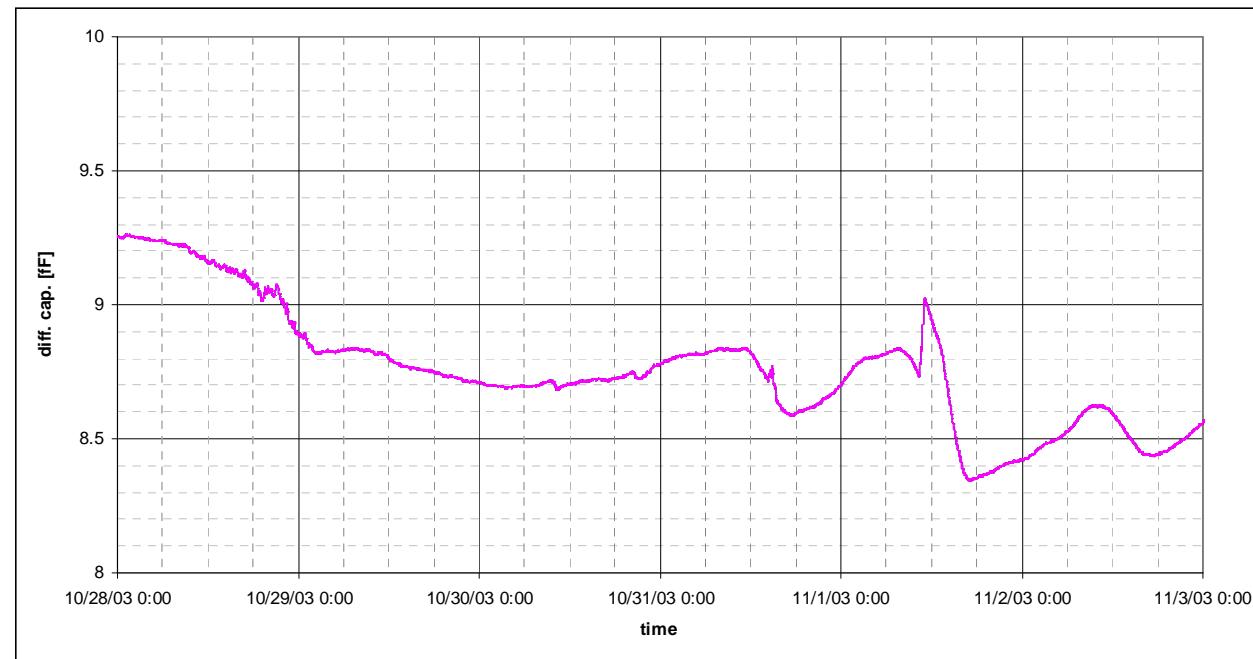
Other sources of errors

- **Humidity variations**
 - at 20°C a change in humidity from 40 to 90% changes the dielectric constant by 200 ppm
- **Temperature variations**
 - Thermal expansion => cancelled in a symmetrical design
 - Effects on the readout electronics: gain and offset variation
 - temperature dependence of dielectric constant (2 $10^{-6}/^{\circ}\text{C}$ for dry air at STP;
700 $10^{-6}/^{\circ}\text{C}$ for moist air)
- **Pressure changes**
 - a pressure change of 1 atm at 20°C changes the dielectric constant by 200 ppm
 - causes dimensional changes (a brass cube of 1 cm contracts by 3 μm for a 1 atm change)
- **Oxidation of surfaces (rodium plating recommended)**
- **Stability of materials (70-30 brass gives good results)**
- **Creep of materials**
- **Relaxation of screw tension**
- **Microseismicity (about 2 μm peak to peak displacement, period 3-8 s)**

Readout: tiltmeter electrical equivalent



TILTMETER ELECTRICAL EQUIVALENT: $TC = 100$ s



Issues:

- Testing: How to generate $<< 1$ nrad tilt for testing?
- Dynamic range:

min. signal ~ 1 zF

max signal $\sim 1 \mu\text{rad} \Rightarrow 50$ bits!!

It will require frequent “zeroing” to be able to limit the dynamic range